

FISCHERSCOPE® X-RAY XDAL® 600: X-ray Fluorescence Analysis can be that Simple

Optimized for Fast, Cost-effective XRF Measurements

With FISCHERSCOPE® X-RAY XDAL® 600, we present a new, universally applicable measuring instrument to the Fischer X-RAY family. The XDAL 600 is designed as a user-friendly X-ray fluorescence (XRF) benchtop instrument for coating thickness measurement and material analysis. It is characterized by a compact, practical design. Nevertheless, it contains the usual precision measurement components. Measure thin layers precisely, quickly and non-destructively. Additionally, XRF analysis of layers with complex compositions or low concentrations is easily achieved.

The Inner Values Count

The XDAL 600 features an electrically interchangeable 4-fold aperture as well as a 3-fold interchangeable primary filter to create ideal excitation conditions for every measurement, resulting in maximum flexibility for a wide range of measurement tasks. With the manually adjustable sample table (scissors table), samples can be positioned quickly and conveniently. Thanks to

the patented DCM (Distance Controlled Measurement) method, even the measurement of complex geometries is straightforward.

Equipped with the Next Generation of Digital Pulse Processors

The XDAL 600 is equipped with the in-house developed digital pulse processor DPP+. Thus, it is possible to process high count rates, translating into maximum measuring precision and shorter measuring times.

Robustness, Accuracy and Long-term Stability

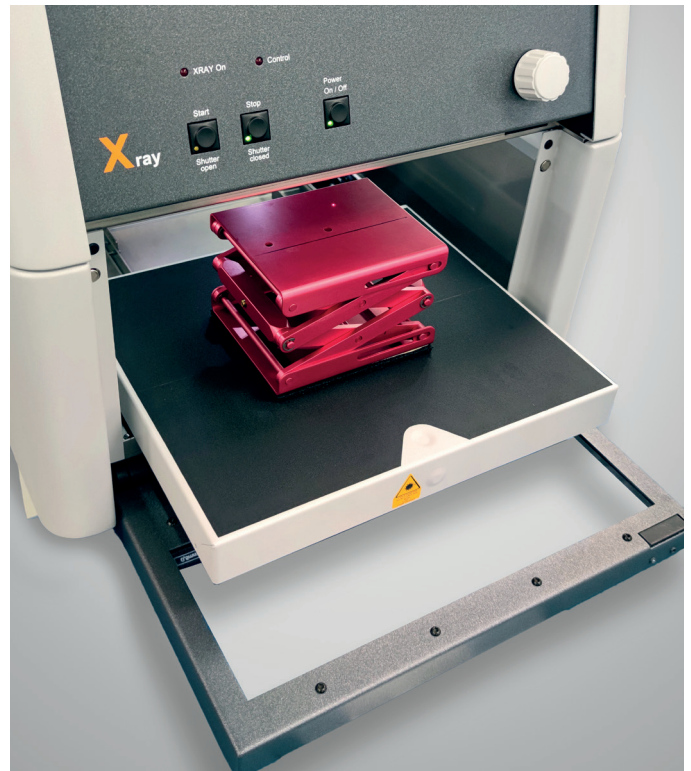
During the development of the XDAL 600, special attention was paid to robustness. In doing so, all prerequisites for a long service life under various conditions, e.g. in electroplating and production, are created. Like the entire Fischer X-RAY portfolio, this device boasts outstanding accuracy and long-term stability. This significantly reduces the calibration effort and saves time and costs.

Applications

- Functional coatings on lead frames, connectors or printed circuit boards in the electronics and semiconductor industries
- Determination of complex multi-coating systems
- Determination of the lead content in solder
- Determination of the phosphorous content in NiP coatings

Features

- XRF measuring instrument fulfils X-ray standards DIN ISO 3497 and ASTM B 568
- Non-destructive material analysis and coating thickness measurement of very thin coatings
- 4x changeable aperture (collimator): \varnothing 0.1 mm (3.9 mils), \varnothing 0.3 mm (11.8 mils), \varnothing 1 mm (39.4 mils), \varnothing 3 mm (118 mils)
- 3x changeable primary filter
- Manually adjustable sample table (scissors table) for quick and easy sample positioning
- Due to its compact design, the XRF instrument is lightweight and requires only little space
- Laser pointer as positioning aid supports the quick alignment of the sample
- High-resolution color video camera simplifies the precise determination of the measurement area
- Operation, evaluation of measurements and clear presentation of measured values via user-friendly Fischer WinFTM® software



Manually adjustable sample table



Contact us

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